News on CPV in mixing using P.R. D*lv and K-tag

•Alessandro Gaz PHD thesis results:

Martino, 4/22/2008

 $|q/p|-1 = xxx \pm 0.0025(stat)\pm 0.0018(syst)\pm 0.0023(bias)$ (2nd best meas. @ B factories)

A good result but:

•|q/p| bias ~ 0.004 from MC, bigger than statistical error;

•Bias reflects in the largest systematic error...

Large bias on τ_{B0} , Δm_{d} :	PDG:
• $\tau_{_{\rm B0}}$ = 1.490±0.004 ps	1.530±0.009 ps
• $\Delta m_d = 0.5699 \pm 0.0022 \text{ ps}^{-1}$	0.507±0.005 ps ⁻¹

Bias to be understood before publication!

Problems of the Unbinned Fit

A) Slowness:

Fit of the full Run1-Run5 data statistics too long (~100 free paramaters);
Split of data set (takes ~ 24 h to fit 5% of the real data statistics);
Result from the average of the different subsample;

B) Convergence difficulty:

•log(Likelihood) shows a structure with secondary minima;

Measured Bias is actually a true effect or is it a feature of the fit instability?Same question about the evaluation of systematic uncertainties;

A) and B) effects interfere: Slowness precludes studies on convergence & stability of the fit.

Solution: Binned Fit

•Binning extended to all the relevant variables:

 Δt , $\sigma(\Delta t)$, P_{K} , $m^{2}v$, $\theta(l-K) = 50K$ bins

8 event categories: $(e/\mu) X$ (Mixed/Unmixed) X (K^+/K^-) *Convergence takes ~ 8 h on the full R1-R5 data statistics! *Result on data compatible with the "Old-Unbinned" fit!

- Go back to the MC in order to:
- Define a strategy to reach the fit convergence;
- Understand at which level of fit complexity the bias does appear (perfect/measured resolution and tagging; only signal/full sample composition);
- Re-blind the fit on real data;

Study of Fit Convergence

•Study the $\Delta \log(L)$ profile around the minimum by performing a set of several fits with a fixed value of a relevant variable x (i.e. |q/p|-1, Δm_d , ...) and

floating all the other parameters;

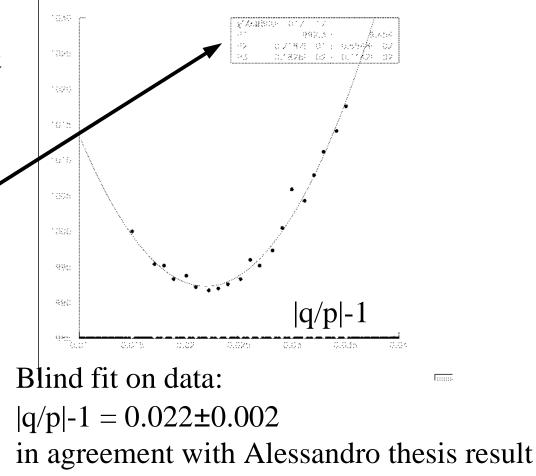
•Determination of the parameter & statistical error directly from the plot by means of a parabolic fit:

 $log(L) = 10g(L_{min}) + \frac{1}{2}((x - x_{min})/\sigma)^2$

 $x_{min} = Best Value$

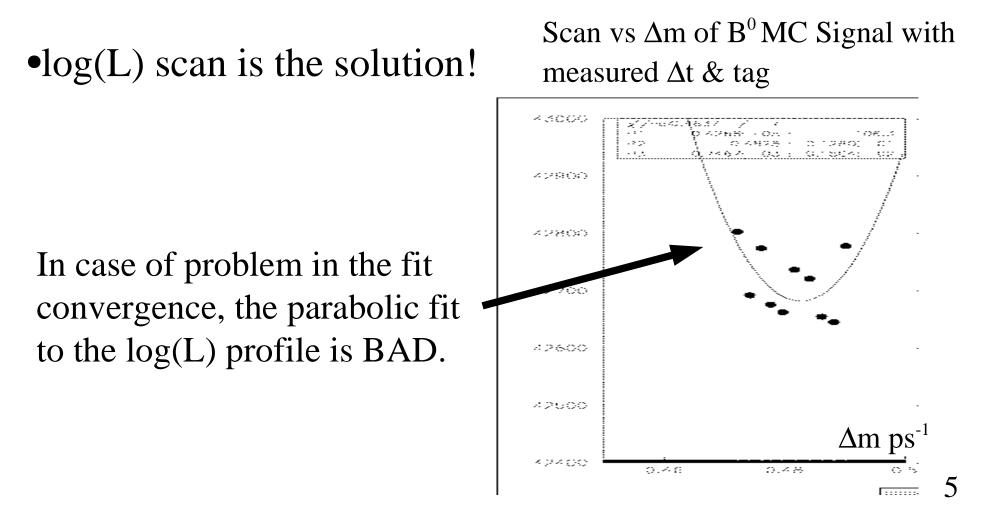
 σ = Statistical Error

To be compared with the nominal fit results



Study of Fit Convergence

•log(L) shows multiple minima: often the fit does not converge to the absolute minimum (minuit status= FAILED, usually Covariance Matrix not positive defined);



Definition of Fit Strategy

Recipe to reach the convergence:

1) Perform the nominal fit;

in case of convergence problems:

2) Launch a scan on Gridka (~10 fits need a few hours);

3) Check if the parabolic fit is good & it gives x_{min} and σ in good agreement with the nominal fit;

4) Otherwise: Launch another fit starting from the parameters corresponding to the lowest minimum of the log(L) in the previous set of fits;

5) Iteratively reach a good log(L) profile;

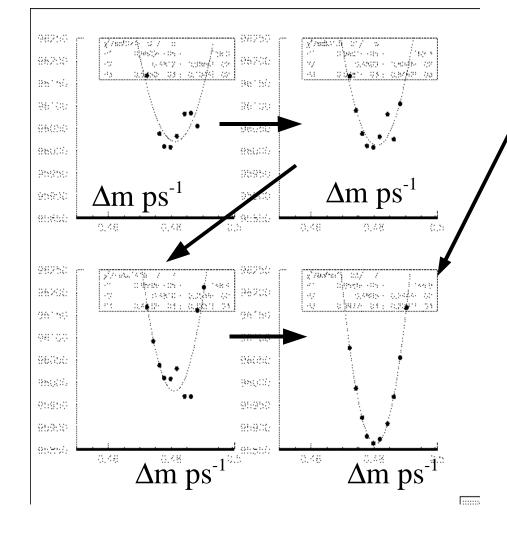
6) Perform the nominal fit starting from the parameters of the best fit of the set;



The nominal fit converges!

Fit Strategy

•Example on MC: $\Delta \log(L)$ vs Δm_d : Signal B⁰ B-tag, Exper. Δt + perfect tag:



 $\Delta m = 0.4805 \pm 0.0004 \text{ ps}^{-1}$

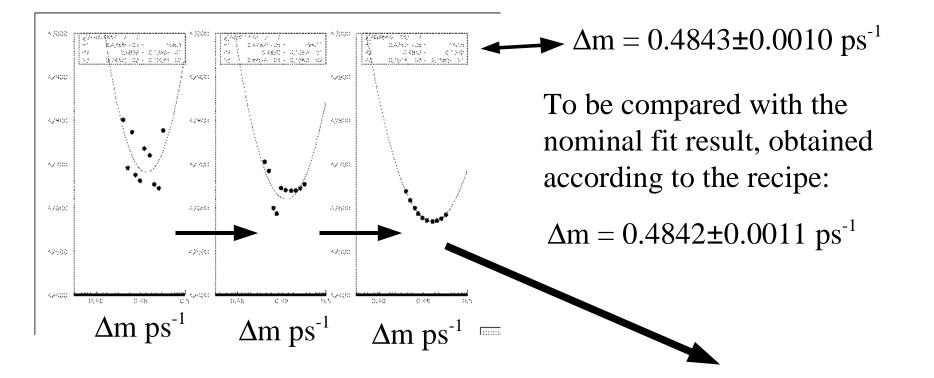
To be compared with the nominal fit result, obtained according to the recipe:

 $\Delta m = 0.4803 \pm 0.0003 \text{ ps}^{-1}$

Very Good agreement found!

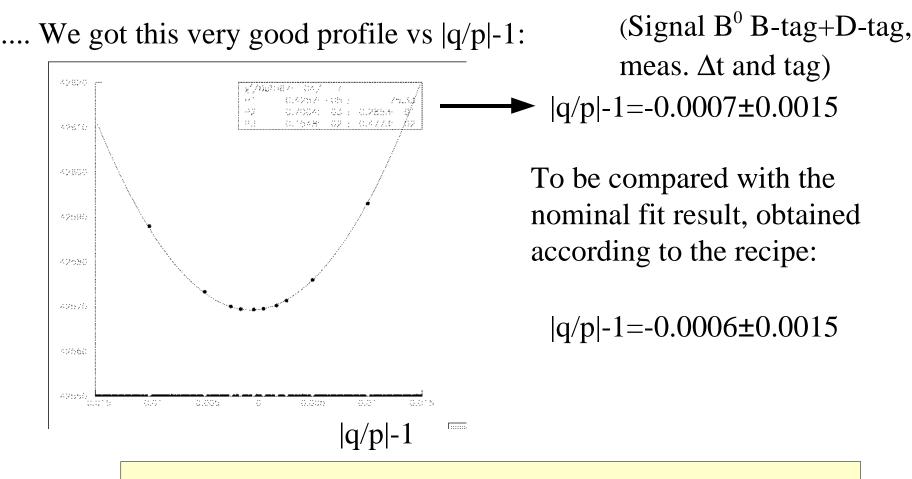
Fit Strategy

•Example on MC: $\Delta \log(L)$ vs Δm_d Signal B⁰ B-tag+D-tag, Exper. Δt and tag:



Starting from the minimum of this last scan vs Δm

Fit Strategy



The Log(L) scan strategy allow us to:



Reach the convergence at the "true" Log(L) minimum;
 Check the statistical error of the nominal fit.

MC Validation: Fit Bias

•Study the bias on τ , Δm , |q/p| step by step, from MC truth to experimental Δt and tagging. Add one component at a time from pure B⁰ signal to full sample composition to see at which level of fit complexity the bias becomes dangerous (if it is the case...).

•Use only CONVERGED fits, obtained by means of the "log(L) Scan" recipe to avoid fit instability effects;

MC-Reference parameters:

$$\tau_{B0} = 1.540 \text{ ps}$$

 $\Delta m = 0.489 \text{ ps}^{-1}$ $\chi_d = 0.1809$
 $|q/p| - 1 = 0$
 $b=0$ Doubly Cabibbo Suppressed
 $c=0$

B⁰ Btag Signal Fit with Perfect Resolution & tagging:

∆t Bins:	20	50	100
$ au_{_{ m B0}}$	0.0183 ± 0.0007	-0.0062±0.0006	-0.0095±0.0006
Δm	-0.0159±0.0002	-0.0049 ± 0.0002	-0.0033±0.0002
b	0.0019 ± 0.0004	0.0021 ± 0.0005	0.0021 ± 0.0005
С	0.0000 ± 0.0005	-0.0003 ± 0.0004	-0.0002 ± 0.0004

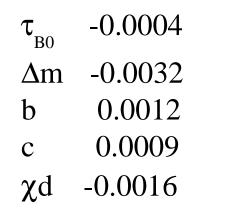
Use at least 50 Δt bins; 100 Δt bins in the following Fitted $\chi_d = 0.1761 \pm 0.0001$ 0.1778 ± 0.0001 0.1780 ± 0.0001 (in good agreement with F(mixed) = 0.1786 \pm 0.0002)

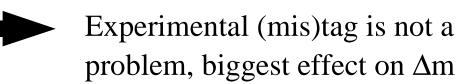
-0.2% selection bias on F(mixed) (MC truth: $\chi_d = 0.1809$) Bias of several Statistical Sigmas on $\tau \& \Delta m$, but <1%.

B⁰ Btag Signal Fit with Perfect Resolution & exp. tagging:

- τ_{B0} -0.0099±0.0006
- ∆m -0.0065±0.0005 → Bias ~ 1.3%
- b 0.0033±0.0007
- c 0.0007±0.0013
- $\chi d -0.0045 \pm 0.0002$

Mistag effect (comparison with previous page result):

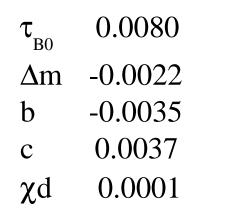


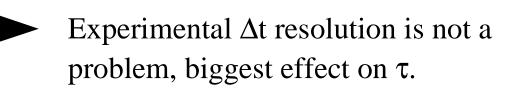


 B^0 Btag Signal Fit with Measured Δt & perfect tagging:

- $\tau_{B0} = -0.0019 \pm 0.0011$
- ∆m -0.0087±0.0003 → Bias ~ 1.8%
- b -0.0002±0.0008
- c 0.0044±0.0009
- χd -0.0044±0.0001

Resolution effect (comparison w.r.t. Perfect Δt & tagging fit):





 B^0 Btag+Dtag Signal Fit with Measured Δt & tagging:

$ au_{_{ m B0}}$	-0.0169±0.0018	→ Bias ~ 1.1%
∆m b c	-0.0048±0.0011 -0.0004±0.0013 -0.0844±0.0019	•As already known, due to the Dtag resolution model, we will not be able to measure DCS parameters b, c.
χd	-0.0049 ± 0.0005	
q/p -1	-0.0006±0.0015	

• τ , Δm show a 1% bias... (nice for just "effective" parameters)... however we have to go on by adding all the missing components to determine the global analysis bias and decide if measure also $\tau \& \Delta m$;

•Very good result on |q/p|.

Next Steps

•Add all the backgrounds (combinatorial, charged B decays, continuum) to the fit and complete the MC validation;

•Finalize the procedure on a BLIND fit to the real data;

•Perform a Toy MC validation;

•Re-determine the Systematic Uncertainties;

•Summer Conference/Publication?

•Alessandro Gaz left the group after two years of fruitful work...

•... but Enrico Feltresi from Dresda is ready to go on!